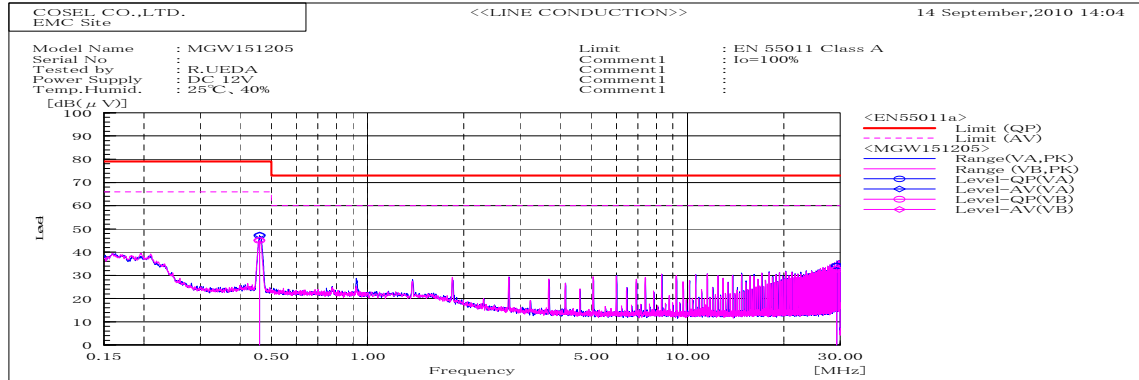
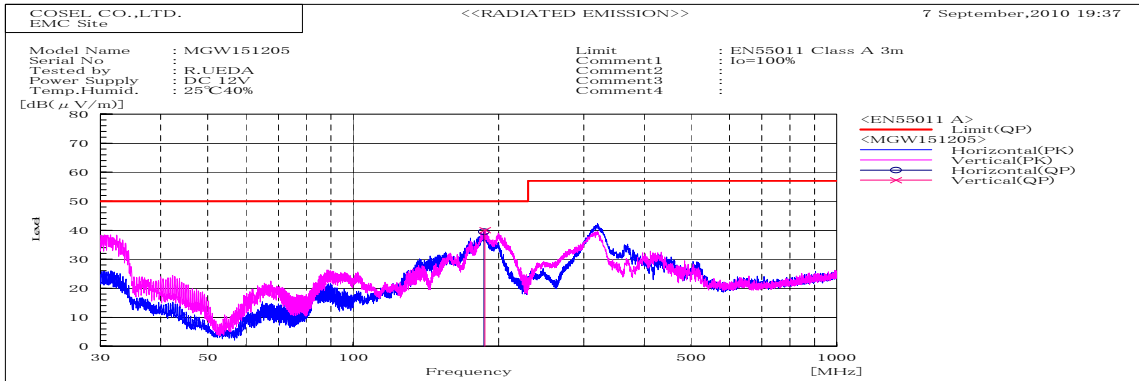


DATA SHEET		Date	21-Sep-10
Model	MGW151205	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	R.Ueda



Frequency MHz	Harm	Line Phase	Reading dB(uV)		Factor dB	Level dB(uV)		Limit dB(uV)		Margin dB		Pass/ Fail	Remark
			QP	AV		QP	AV	QP	AV	QP	AV		
0.45956		VB	35	35.1	10	45	45.1	79	66	34	20.9	Pass	
0.45984		VA	37	37.2	10.1	47.1	47.3	79	66	31.9	18.7	Pass	
29.25385		VB	21.5	21.9	11	32.5	32.9	73	60	40.5	27.1	Pass	
29.2534		VA	23.5	23.5	10.6	34.1	34.1	73	60	38.9	25.9	Pass	



Frequency MHz	Polarization	Stability	Reading dB(uV)		Space Loss dB	Level dB(mW)		Margin dB	Pass/Fail	Height cm	Angle deg	Remark
			QP	AV		QP	AV					
186.31	H	Stable	61.7	-22.2		39.5		10.5	Pass	150	323	
187.338	V	Stable	62.1	-22.1		40		10	Pass	147	252	

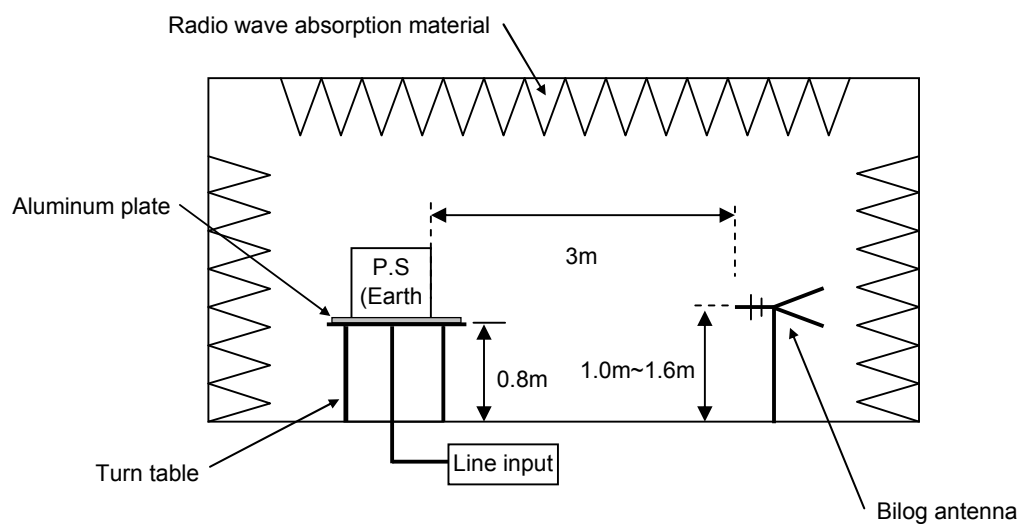
# DATA SHEET

Model	Circuit used for measurement
Test	EMI Line conduction & Radiated emission

## 1. Line conduction



## 2. Radiated emission



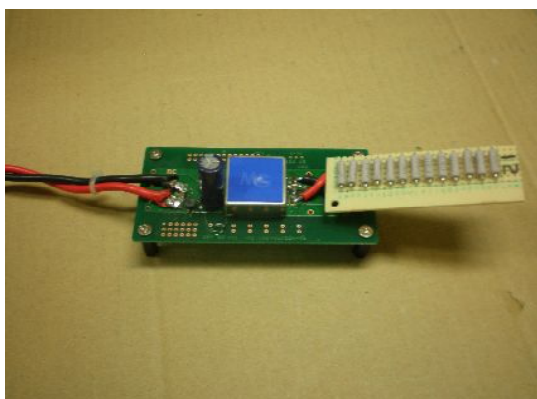


## Conditions

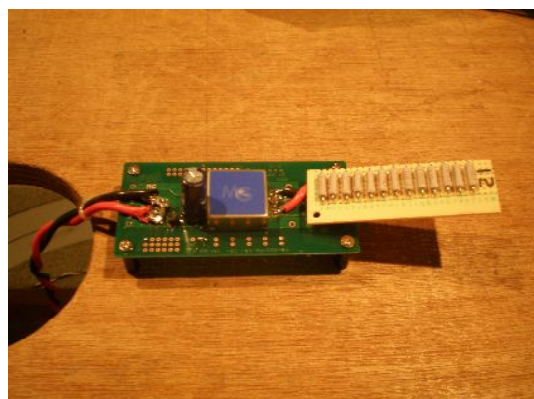
Test : EMI  
Model Name : MGS1512□□/MGW1512□□

○Photographs of Test Set-Up

### LINE CONDUCTION



### RADIATED EMISSION



○Testing circuitry

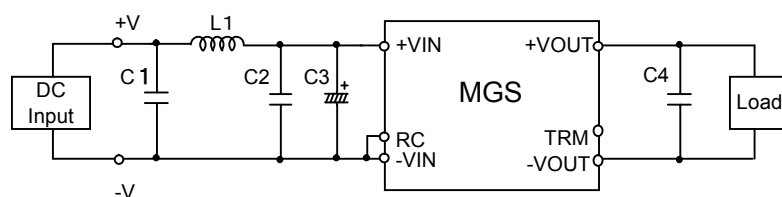


Fig.1 Testing circuitry 1

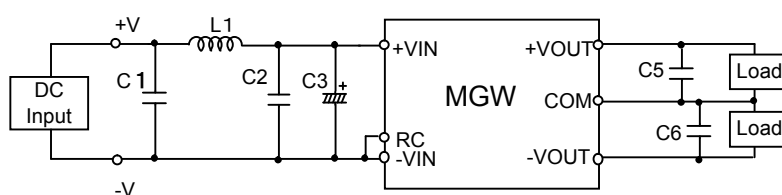


Fig.2 Testing circuitry 2

L1	: 0.5 $\mu$ H	CI4C-0R5	(KORIN ELECTRONICS)
C1,C2	: 25V 10 $\mu$ F	CM316X5R106K25A	(KYOCERA)
C3	: 50V 220 $\mu$ F	LXY50VB220M	(NIPPON CHEMI-CON)
C4,C5,C6	: 25V 22 $\mu$ F	CM32X5R226K25A	(KYOCERA)